

TOSHIBA PHOTOCOUPLER GaAlAs IRED &amp; PHOTO-IC

**T L P 2 5 0**

TRANSISTOR INVERTER  
 INVERTER FOR AIR CONDITIONER  
 IGBT GATE DRIVE  
 POWER MOS FET GATE DRIVE

The TOSHIBA TLP250 consists of a GaAlAs light emitting diode and a integrated photodetector.

This unit is 8-lead DIP package.

TLP250 is suitable for gate driving circuit of IGBT or power MOS FET.

- Input Threshold Current :  $I_F = 5\text{mA}$  (Max.)
- Supply Current ( $I_{CC}$ ) :  $11\text{mA}$  (Max.)
- Supply Voltage ( $V_{CC}$ ) :  $10\text{-}35\text{V}$
- Output Current ( $I_O$ ) :  $\pm 1.5\text{A}$  (Max.)
- Switching Time ( $t_{pLH}/t_{pHL}$ ) :  $1.5\mu\text{s}$  (Max.)
- Isolation Voltage :  $2500\text{V}_{\text{rms}}$  (Min.)
- UL Recognized : UL1577, File No.E67349
- Option (D4) type

VDE Approved : DIN VDE0884 / 06.92, Certificate No.76823

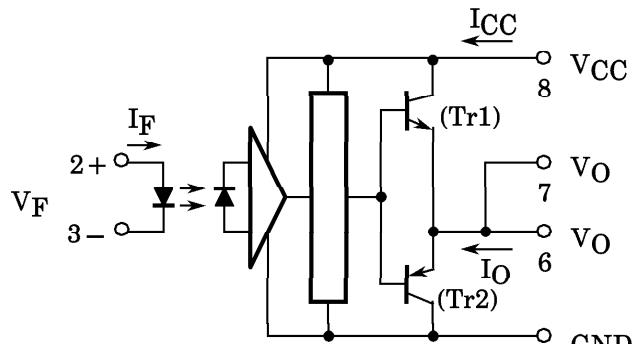
Maximum Operating Insulation Voltage :  $630\text{V}_{\text{PK}}$

Highest Permissible Over Voltage :  $4000\text{V}_{\text{PK}}$

(Note) When a VDE0884 approved type is needed,  
please designate the "Option (D4)"

- Creepage Distance :  $6.4\text{mm}$  (Min.)
- Clearance :  $6.4\text{mm}$  (Min.)

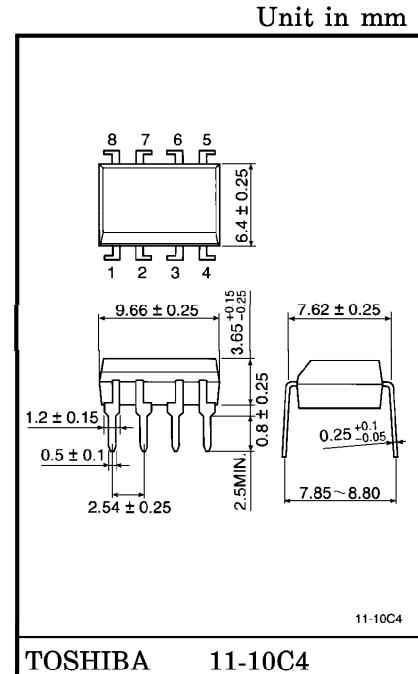
## SCHMATIC



A  $0.1\mu\text{F}$  bypass capacitor must be connected between pin 8 and 5 (See Note 5).

## TRUTH TABLE

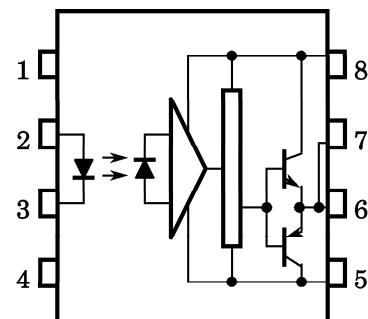
		Tr1	Tr2
Input LED	ON	ON	OFF
	OFF	OFF	ON



TOSHIBA 11-10C4

Weight : 0.54g

## PIN CONFIGURATION (TOP VIEW)



- 1 : N.C.
- 2 : ANODE
- 3 : CATHODE
- 4 : N.C.
- 5 : GND
- 6 :  $V_O$  (OUTPUT)
- 7 :  $V_O$
- 8 :  $V_{CC}$

ABSOLUTE MAXIMUM RATINGS ( $T_a = 25^\circ\text{C}$ )

CHARACTERISTIC		SYMBOL	RATING	UNIT
LED	Forward Current	$I_F$	20	mA
	Forward Current Derating ( $T_a \geq 70^\circ\text{C}$ )	$\Delta I_F / \Delta T_a$	-0.36	mA / °C
	Peak Transient Forward Current (Note 1)	$I_{FPT}$	1	A
	Reverse Voltage	$V_R$	5	V
	Junction Temperature	$T_j$	125	°C
DETECTOR	"H" Peak Output Current ( $P_W \leq 2.5\mu\text{s}$ , $f \leq 15\text{kHz}$ ) (Note 2)	$I_{OPH}$	-1.5	A
	"L" Peak Output Current ( $P_W \leq 2.5\mu\text{s}$ , $f \leq 15\text{kHz}$ ) (Note 2)	$I_{OPL}$	+1.5	A
	Output Voltage ( $T_a \leq 70^\circ\text{C}$ )	$V_O$	35	V
	( $T_a = 85^\circ\text{C}$ )		24	
	Supply Voltage ( $T_a \leq 70^\circ\text{C}$ )	$V_{CC}$	35	V
	( $T_a = 85^\circ\text{C}$ )		24	
	Output Voltage Derating ( $T_a \geq 70^\circ\text{C}$ )	$\Delta V_O / \Delta T_a$	-0.73	V / °C
	Supply Voltage Derating ( $T_a \geq 70^\circ\text{C}$ )	$\Delta V_{CC} / \Delta T_a$	-0.73	V / °C
	Junction Temperature	$T_j$	125	°C
Operating Frequency (Note 3)		$f$	25	kHz
Operating Temperature Range		$T_{opr}$	-20~85	°C
Storage Temperature Range		$T_{stg}$	-55~125	°C
Lead Soldering Temperature (10s)		$T_{sol}$	260	°C
Isolation Voltage (AC, 1min., R.H. $\leq 60\%$ ) (Note 4)		$BV_S$	2500	Vrms

(Note 1) Pulse width  $P_W \leq 1\mu\text{s}$ , 300pps

(Note 2) Exponential Waveform

(Note 3) Exponential Waveform,  $I_{OPH} \leq -1.0\text{A}$  ( $\leq 2.5\mu\text{s}$ ),  $I_{OPL} \leq +1.0\text{A}$  ( $\leq 2.5\mu\text{s}$ )

(Note 4) Device considered a two terminal device : pins 1,2,3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

(Note 5) A ceramic capacitor ( $0.1\mu\text{F}$ ) should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching property. The total lead length between capacitor and coupler should not exceed 1cm.

## RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT
Input Current, ON	$I_F(\text{ON})$	7	8	10	mA
Input Voltage, OFF	$V_F(\text{OFF})$	0	—	0.8	V
Supply Voltage	$V_{CC}$	15	—	30	V
Peak Output Current	$I_{OPH} / I_{OPL}$	—	—	±0.5	A
Operating Temperature	$T_{opr}$	-20	25	70	°C

## ELECTRICAL CHARACTERISTICS (Ta = -20~70°C, Unless otherwise specified)

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION		MIN.	TYP.*	MAX.	UNIT
Input Forward Voltage	V <sub>F</sub>	—	I <sub>F</sub> =10mA, Ta=25°C		—	1.6	1.8	V
Temperature Coefficient of Forward Voltage	ΔV <sub>F</sub> / ΔTa	—	I <sub>F</sub> =10mA		—	-2.0	—	mV / °C
Input Reverse Current	I <sub>R</sub>	—	V <sub>R</sub> =5V, Ta=25°C		—	—	10	μA
Input Capacitance	C <sub>T</sub>	—	V=0, f=1MHz, Ta=25°C		—	45	250	pF
Output Current	“H” Level	I <sub>OPH</sub>	3	V <sub>CC</sub> =30V (*1)	I <sub>F</sub> =10mA V <sub>8-6</sub> =4V	-0.5	-1.5	—
	“L” Level	I <sub>OPL</sub>	2		I <sub>F</sub> =0 V <sub>6-5</sub> =2.5V	0.5	2	—
Output Voltage	“H” Level	V <sub>OH</sub>	4	V <sub>CC1</sub> =+15V, V <sub>EE1</sub> =-15V R <sub>L</sub> =200Ω, I <sub>F</sub> =5mA		11	12.8	—
	“L” Level	V <sub>OL</sub>	5	V <sub>CC1</sub> =+15V, V <sub>EE1</sub> =-15V R <sub>L</sub> =200Ω, V <sub>F</sub> =0.8V		—	-14.2	-12.5
Supply Current	“H” Level	I <sub>CCH</sub>	—	V <sub>CC</sub> =30V, I <sub>F</sub> =10mA Ta=25°C		—	7	—
	“L” Level	I <sub>CCL</sub>	—	V <sub>CC</sub> =30V, I <sub>F</sub> =10mA Ta=25°C		—	—	11
	“H” Level	I <sub>CCH</sub>	—	V <sub>CC</sub> =30V, I <sub>F</sub> =0mA Ta=25°C		—	7.5	—
	“L” Level	I <sub>CCL</sub>	—	V <sub>CC</sub> =30V, I <sub>F</sub> =0mA Ta=25°C		—	—	11
Threshold Input Current	“Output L→H”	I <sub>FLH</sub>	—	V <sub>CC1</sub> =+15V, V <sub>EE1</sub> =-15V R <sub>L</sub> =200Ω, V <sub>O</sub> >0V		—	1.2	5
Threshold Input Voltage	“Output H→L”	V <sub>FHL</sub>	—	V <sub>CC1</sub> =+15V, V <sub>EE1</sub> =-15V R <sub>L</sub> =200Ω, V <sub>O</sub> <0V		0.8	—	—
Supply Voltage	V <sub>CC</sub>	—			10	—	35	V
Capacitance (Input-Output)	C <sub>S</sub>	—	V <sub>S</sub> =0, f=1MHz Ta=25°C		—	1.0	2.0	pF
Resistance (Input-Output)	R <sub>S</sub>	—	V <sub>S</sub> =500V, Ta=25°C R.H.≤60%		1×10 <sup>12</sup>	10 <sup>14</sup>	—	Ω

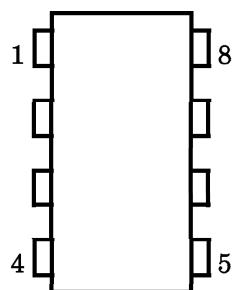
\* All typical values are at Ta=25°C      (\*1) : Duration of I<sub>O</sub> time≤50μs

## SWITCHING CHARACTERISTICS (Ta = -20~70°C, Unless otherwise specified)

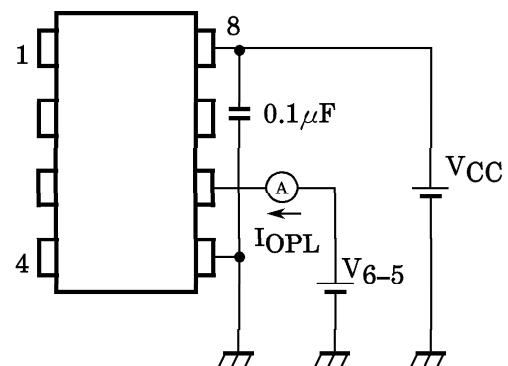
CHARACTERISTIC		SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.*	MAX.	UNIT
Propagation Delay Time	L→H	t <sub>pLH</sub>	6	I <sub>F</sub> =8mA V <sub>CC1</sub> =+15V, V <sub>EE1</sub> =-15V R <sub>L</sub> =200Ω	—	0.15	0.5	μs
	H→L	t <sub>pHL</sub>			—	0.15	0.5	
Output Rise Time		t <sub>r</sub>			—	—	—	
Output Fall Time		t <sub>f</sub>			—	—	—	
Common Mode Transient Immunity at High Level Output		C <sub>MH</sub>	7	V <sub>CM</sub> =600V, I <sub>F</sub> =8mA V <sub>CC</sub> =30V, Ta=25°C	-5000	—	—	V / μs
Common Mode Transient Immunity at Low Level Output		C <sub>ML</sub>	7	V <sub>CM</sub> =600V, I <sub>F</sub> =0mA V <sub>CC</sub> =30V, Ta=25°C	5000	—	—	V / μs

\* All typical values are at Ta=25°C

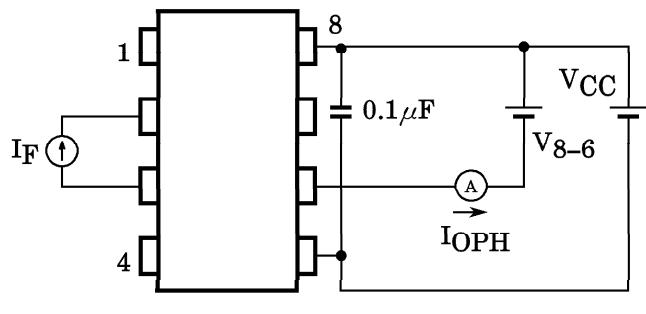
TEST CIRCUIT 1 :



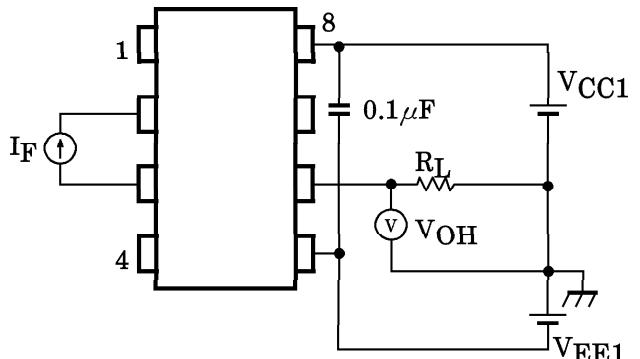
TEST CIRCUIT 2 : IOPL



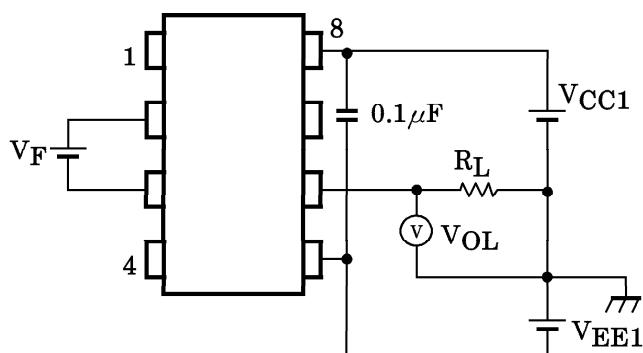
TEST CIRCUIT 3 : IOPH



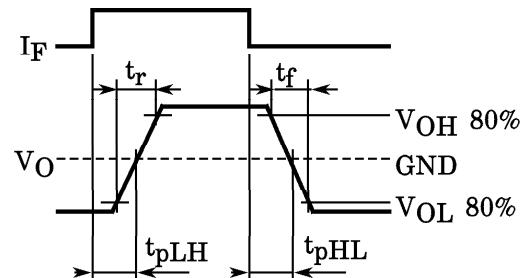
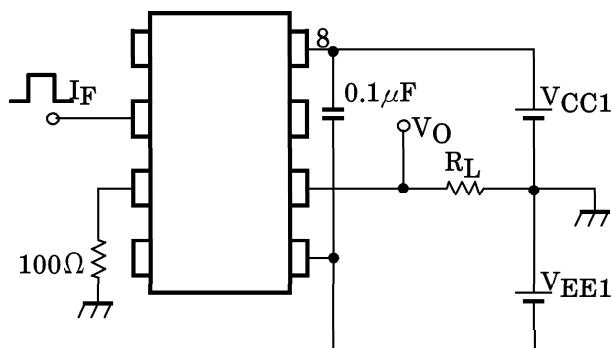
TEST CIRCUIT 4 : VOH



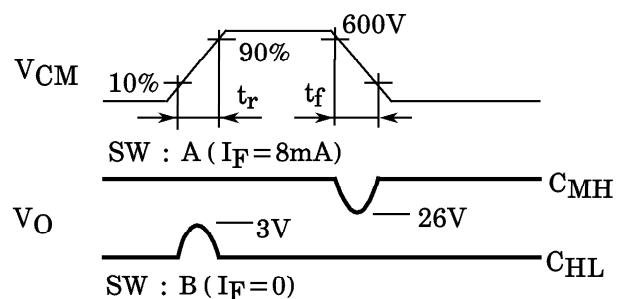
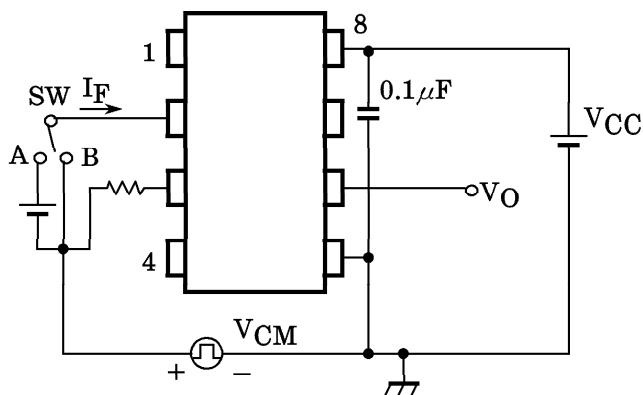
TEST CIRCUIT 5 : VOL



TEST CIRCUIT 6 :  $t_{pLH}$ ,  $t_{pHL}$ ,  $t_r$ ,  $t_f$



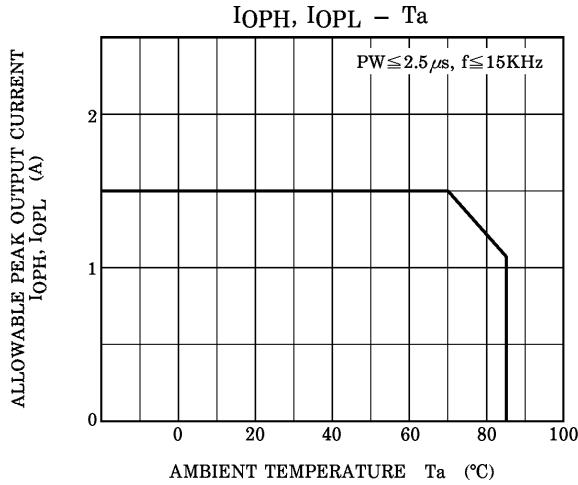
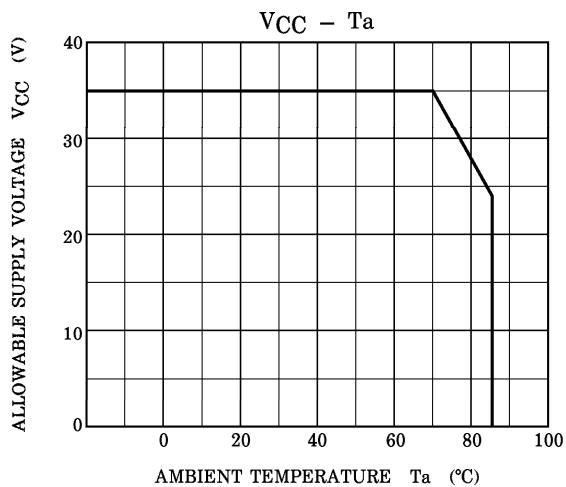
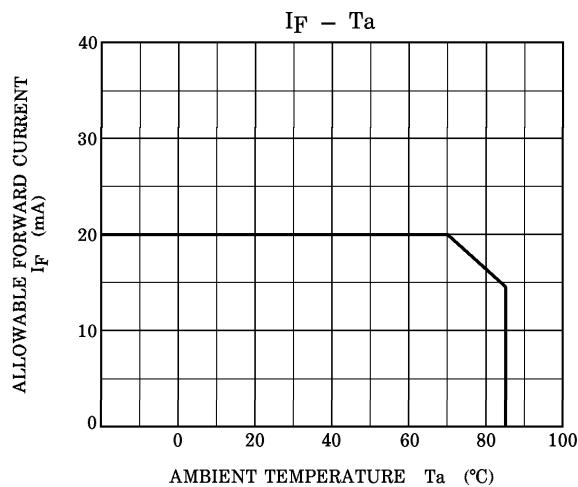
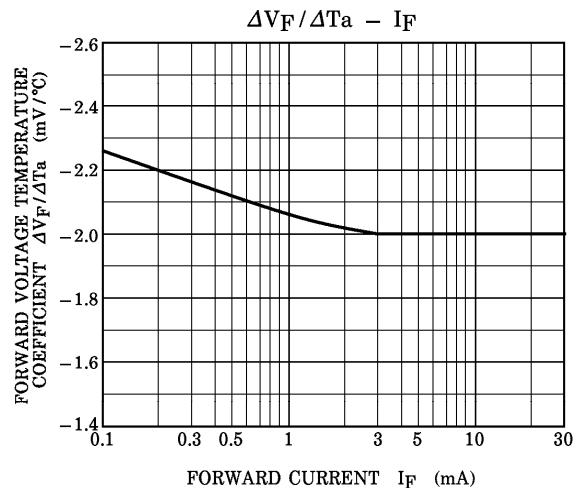
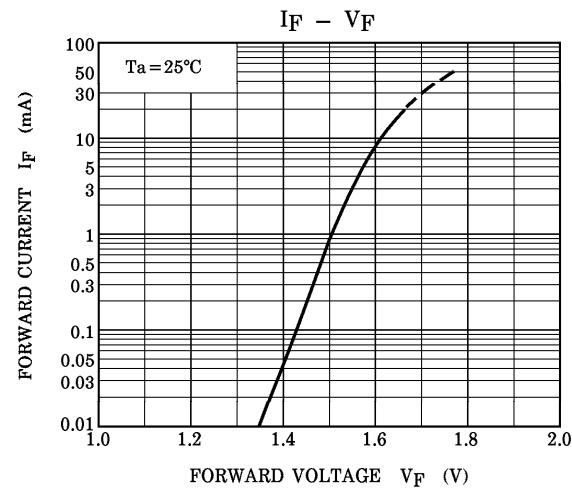
TEST CIRCUIT 7 :  $C_{ML}$ ,  $C_{MH}$



$$C_{ML} = \frac{480(V)}{t_r(\mu s)}$$

$$C_{MH} = \frac{480(V)}{t_f(\mu s)}$$

$C_{ML}$  ( $C_{MH}$ ) is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the low (high) state.



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000707EBC

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